

Electronic Supplementary Information

Evolution of Charge Pathways Through Amorphous Aluminum-Cerium Electrode for Stable Organic Photovoltaics

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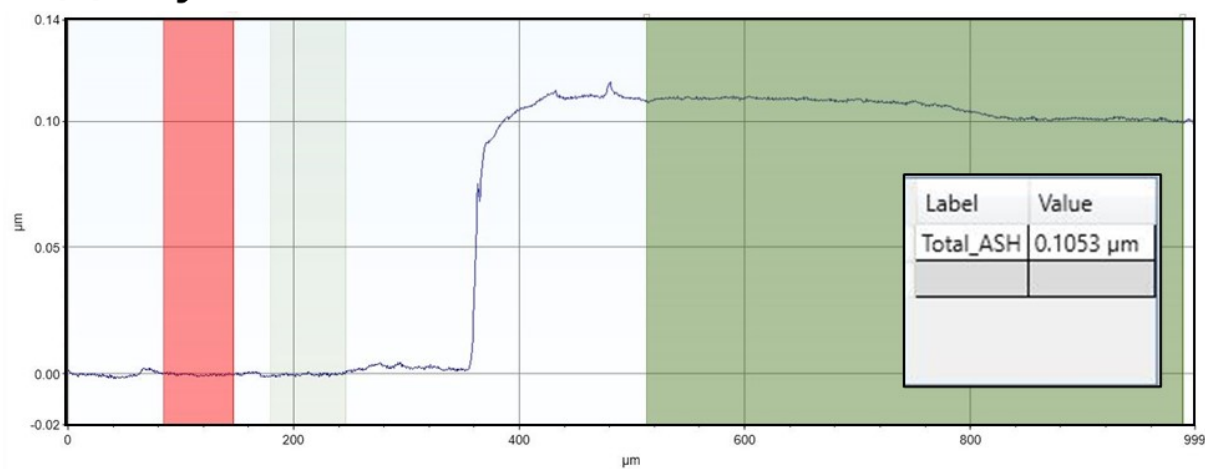
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Table S1 Summary of electrical parameters of OPV devices with crystalline Al and amorphous AlCe electrodes before and after aging in ambient air for 24 hours.

	V_{oc} (V)	J_{sc} (mA/cm²)	J_{sc, EQE} (mA/cm²)	FF	PCE (%)
Ag (Pristine)	0.928	17.21	19.79	0.63	10.06
Ag (24 h)	0.718	3.92	-	0.28	0.79
AlCe (Pristine)	1.026	16.95	17.02	0.57	9.92
AlCe (24 h)	1.121	18.06	17.27	0.50	10.03

(a) Crystalline Al



(b) Amorphous AlCe

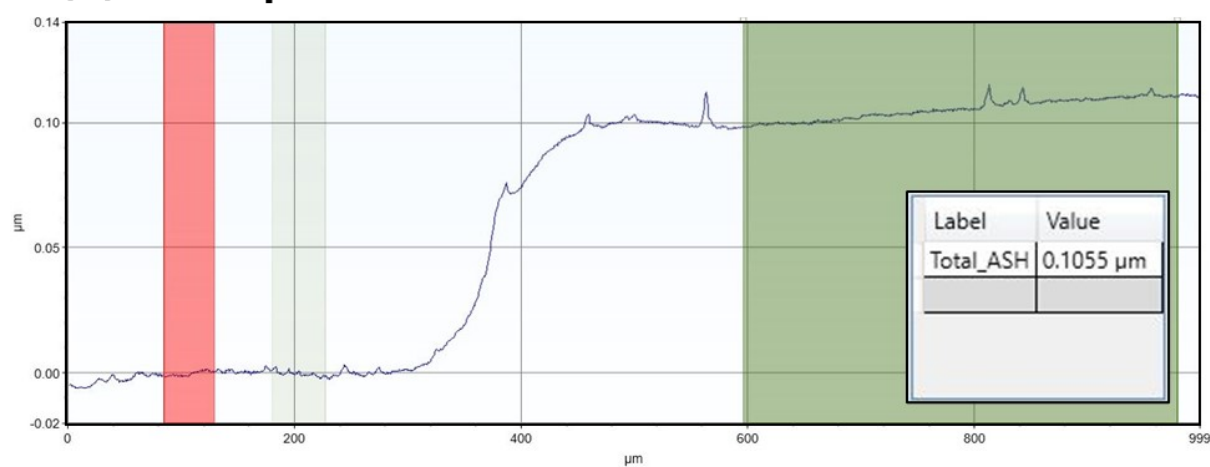


Fig. S1 Thickness measurement of sputtered crystalline Al and amorphous AlCe thin films with Alpha-step surface profiler showing that the electrodes with thicknesses of 100nm were obtained.

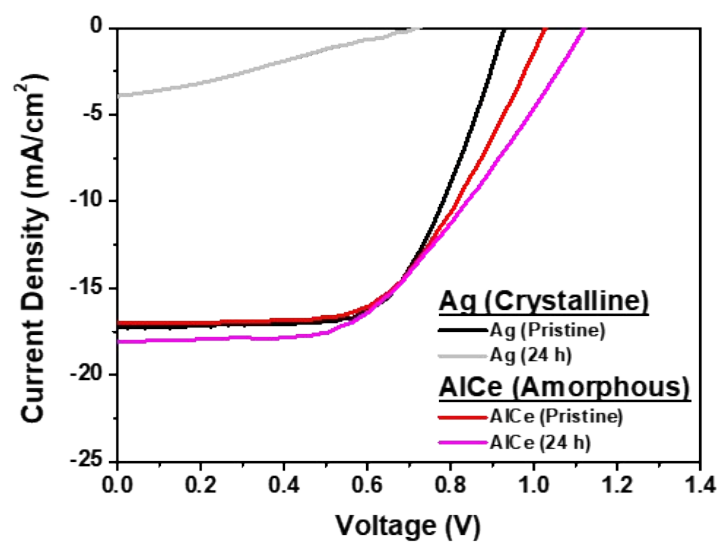


Fig. S2 J-V curves obtained from OPV devices with Ag and AlCe electrode, with current density (y-axis) in linear scale.

(a) Crystalline Al



Avg. resistivity : $6.46 \mu\Omega \cdot \text{cm}$

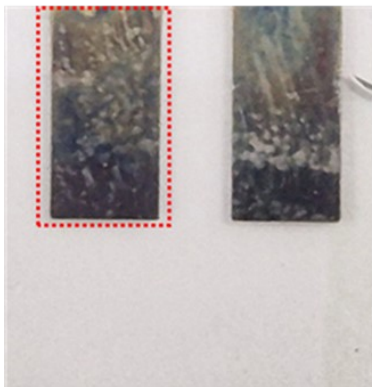
(b) Amorphous AlCe



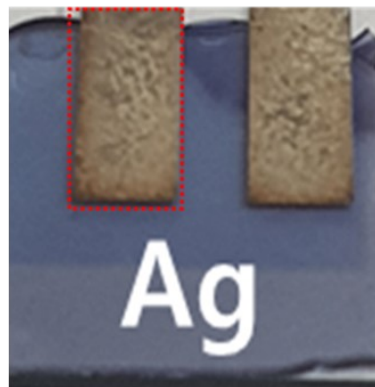
Avg. resistivity : $48.9 \mu\Omega \cdot \text{cm}$

Fig. S3 Resistivity measurements of (a) crystalline Al and (b) amorphous AlCe electrode

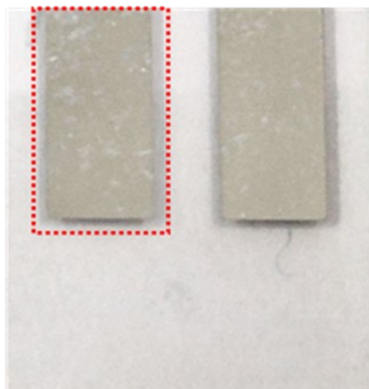
(a) Ag on ITO



(b) OPV w/ Ag



(c) AlCe on ITO



(d) OPV w/ AlCe

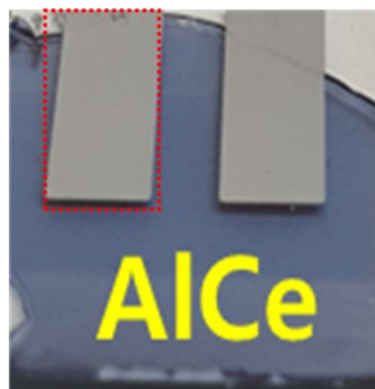


Fig. S4 Photographs of electrodes after storage in air for 1000 h. (a) Ag on ITO substrate, (b) Ag on OPV structure, (ITO/ZnO/PCE10:IEICO-4F/MoO_x) (c) AlCe on ITO substrate, and (d) AlCe on OPV structure

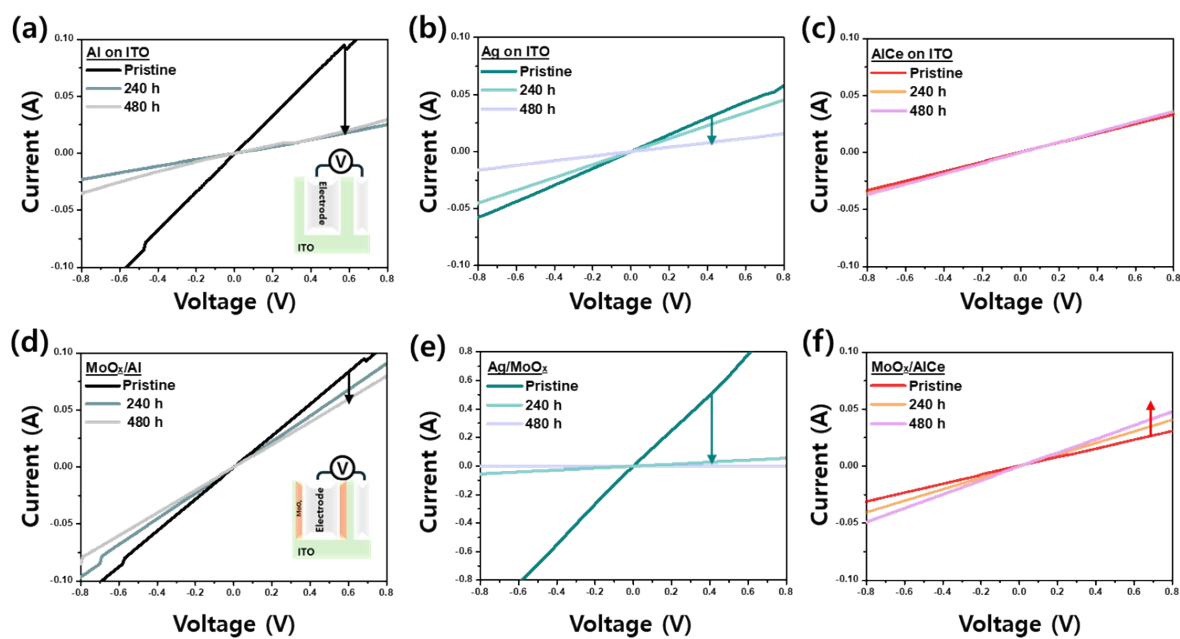


Fig. S5 I-V analyses on electronic conductivity at the interface between the electrodes (Al, Ag, and AlCe) and ITO (a, b, c) and the electrodes and MoO₃ layer (d, e, f) during storage in ambient air. The inset shows the sample structure used for the analyses.